# TOSHIBA

## **TOSHIBA PHOTOCOUPLER**

# TLP181(V4)

ATTACHMENT: SPECIFICATIONS FOR VDE0884 OPTION

Types: TLP181

Type designations for 'Option: (V4)', which are tested under VDE0884 requirements.

Ex. : TLP181 (V4-GR-TPR) V4 : VDE0884 option

GR: CTR rank name

TPR : standard taping name

Note : Use Toshiba standard type number for safety standard application.

Ex. TLP181 (V4-GR-TPR)  $\rightarrow$  TLP181

#### **VDE0884 ISOLATION CHARACTERISTICS**

DESCRIPTION	SYMBOL	RATING	UNIT
$\begin{array}{c} \textbf{Application Classification} \\ \textbf{(DIN VDE0110 Teil 1/01.89, Table 1)} \\ \textbf{for rated mains voltage} \leqq 150 \ V_{RMS} \\ \textbf{for rated mains voltage} \leqq 300 \ V_{RMS} \\ \end{array}$		I-IV I-III	_
Climatic Classification (DIN IEC68 Teil 1/09.80)		55 / 100 / 21	_
Pollution Degree (DIN VDE0110 Teil 1/01.89)	-	2	
Maximum Operating Insulation Voltage	U <sub>IORM</sub>	565	Vpk
Input to output Test Voltage, Method A Upr= $1.5 \times V_{\rm IORM}$ , Type and Sample Test $t_{\rm p}$ = $60{\rm sec}$ , Partial Discharge $< 5{\rm pC}$	Upr	850	Vpk
Input to output Test Voltage, Method B Upr=1.875×V <sub>IORM</sub> , 100% Production Test t <sub>p</sub> =1sec, Partial Discharge<5pC	Upr	1060	Vpk
Highest Permissible Overvoltage (Transient Overvoltage, t <sub>pr</sub> =10s)	$U_{\mathrm{TR}}$	6000	Vpk
Safety Limiting Values (Max. permissible ratings in case of fault, also refer to thermal derating curve  Current (Input current If, Ps=0)  Power (Output or Total Power Dissipation)  Temperature	$egin{array}{c}  ext{I}_{ ext{Si}} \  ext{P}_{ ext{Si}} \  ext{T}_{ ext{Si}} \end{array}$	250 400 150	mA mW °C
Insulation Resistance, $V_{IO} = 500 \text{V}$ , $T_a = 25 ^{\circ}\text{C}$ $V_{IO} = 500 \text{V}$ , $T_a = 100 ^{\circ}\text{C}$ $V_{IO} = 500 \text{V}$ , $T_a = T_s$	R <sub>si</sub>		Ω

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#### INSULATION RELATED SPECIFICATIONS

Minimum Creepage Distance *	Cr	4.0 mm
Minimum Clearance *	Cl	4.0 mm
Minimum Insulation Thickness	ti	0.4 mm
Comperative Tracking Index (DIN IEC112/VDE0303, Part 1)	CTI	175 (VDE0110 Teil 1/01.89 Group Ⅲa)

- in accordance with DIN VDE0110 Teil 1/01.89, Table 2, & 4)
- 1. If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value. If this is not permissible, the user shall take suitable measures.
- 2. This photocoupler is suitable for 'safe electrical isolation' only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits. (Dieses Koppelelement ist fur "Sichere Elektrische Trennung" nur innerhalb der Sicherheitsgrenzdaten geeignet. Die Einhaltung der Sicherheitsgrenzen mu $\beta$  durch Schutzschaltungen sichergestellt sein.)

**TLP181** 

VDE Test sign : Marking on product

for VDE0884

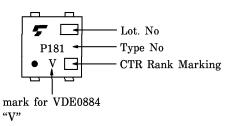
Marking on paking

for VDE0884





Marking Example:

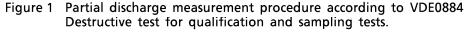


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## Method A

(for type and sampling tests, destructive tests)

$$\begin{array}{lll} t_1,\ t_2 & = 1\ \text{to}\ 10s \\ t_3,\ t_4 & = 1s \\ t_P \text{ (Measuring time for partial discharge)} = 50s \\ t_b & = 62s \\ t_{ini} & = 10s \end{array}$$

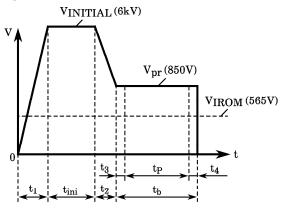


Figure 2 Partial discharge measurement procedure according to VDE0884 Non-desturctive test for 100% inspection.

#### Method B

(for sample test, non-destructive test)

 $\begin{array}{l} t_3,\,t_4 & = 0.1s \\ t_P\,(Measuring\ time\ for\ partial\ discharge) = 1s \\ t_h & = 1.2s \end{array}$ 

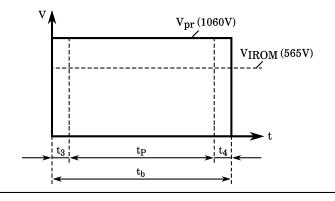


Figure 3 Dependency of maximun safety ratings on ambient temperature

